


<b>Search Notes</b>  	<b>Application/Control No.</b>  10560517	<b>Applicant(s)/Patent Under Reexamination</b>  ALI-HACKL ET AL.
	<b>Examiner</b>  HUY D NGUYEN	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
370	350, 318	10/23/2008	HN
455	13.4, 522, 127.1	10/23/2008	HN
Updated search	same as above	4/27/2009	HN

SEARCH NOTES		
Search Notes	Date	Examiner
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	10/23/2008	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	4/27/2009	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--